



# Compound Semiconductor Materials Committee China TC Chapter Joint Meeting Summary and Minutes

China Spring Standards Meeting 2025

June 17<sup>th</sup>, 2025, 13:00-15:30

Virtual

## TC Chapter Announcements

*Next TC Chapter Meeting*

China Fall Standards Meeting 2025

TBD, China, 2025

## Table 1 Meeting Attendees

*Italics indicate virtual participants*

**Co-Chairs:** Jiangbo Wang (HC SEMITEK), Guoyou Liu(CRRC TIMES)

**SEMI Staff:** Sara Ma (SEMI China), Cassie Li ( SEMI China), Hailey Yan (SEMI China), Ella Jin (SEMI China)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>HC SEMITEK</i>	<i>Wang</i>	<i>Jiangbo</i>	<i>WEIDIANZ</i>	<i>Liu</i>	<i>Zhibin</i>
<i>CRRC TIMES</i>	<i>Liu</i>	<i>Guoyou</i>	<i>Raphaeloptech</i>	<i>Liu</i>	<i>Jinglun</i>
<i>Runxin Micro</i>	<i>Wang</i>	<i>Ronghua</i>	<i>Perfect Crystal</i>	<i>Zhang</i>	<i>Jiaqi</i>
<i>SEMILAB</i>	<i>Márton</i>	<i>Attila</i>	<i>Sinopatt</i>	<i>Zhang</i>	<i>Neng</i>
<i>SEMILAB</i>	<i>Vigh</i>	<i>Benjámín</i>	<i>Tssst</i>	<i>Li</i>	<i>Ruiping</i>
<i>SEMILAB</i>	<i>Ji</i>	<i>Bovey</i>	<i>HIT</i>	<i>Gan</i>	<i>Yang</i>
<i>Fraunhofer IISB</i>	<i>Kranert</i>	<i>Christian</i>	<i>Perfect Crystal</i>	<i>Lu</i>	<i>Min</i>
<i>Zhejiang University</i>	<i>Wu</i>	<i>Zuozuo</i>	<i>Nata</i>	<i>Chen</i>	<i>Huabing</i>
<i>TMJT</i>	<i>Ren</i>	<i>Diansheng</i>	<i>Engitist</i>	<i>Chen</i>	<i>Bimei</i>
<i>Enkris</i>	<i>Tao</i>	<i>Guoqiao</i>	<i>AMEC</i>	<i>Ma</i>	<i>Ziguang</i>
<i>SEMI JAPAN</i>	<i>Yoshida</i>	<i>Akiko</i>	<i>CSA Group</i>	<i>Chen</i>	<i>Roy</i>

## Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
<i>Compound Semiconductor Materials</i>		
None		

## Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
<i>Compound Semiconductor Materials</i>	
None	



**Table 4 Ballot Results**

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
<i>Compound Semiconductor Materials</i>		
6769C	New Standard: Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic Effect	<b>Failed</b> and returned to the TF for rework

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

**Table 5 Activities Approved by the GCS between meetings of the TC Chapter**

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
<i>Compound Semiconductor Materials</i>			
None			

**Table 6 Authorized Activities**

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
<i>Compound Semiconductor Materials</i>			
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

**Table 7 Authorized Ballots**

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
<i>Compound Semiconductor Materials</i>			
None			

**Table 8 SNARF(s) Granted a One-Year Extension**

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
<i>Compound Semiconductor Materials</i>			
None			

**Table 9 SNARF(s) Abolished**

<i>#</i>	<i>TF</i>	<i>Title</i>
<i>Compound Semiconductor Materials</i>		
None		



**Table 10 Standard(s) to receive Inactive Status**

<i>Standard Designation</i>	<i>Title</i>
<i>Compound Semiconductor Materials</i>	
None	

**Table 11 New Action Items**

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>Compound Semiconductor Materials</i>		
None		

**Table 12 Previous Meeting Action Items**

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>Compound Semiconductor Materials</i>		
None		

**1 Welcome, Reminders, and Introductions**

Committee co-chair Jiangbo Wang chaired the meeting and welcomed all attendees including the online attendees. All the attendees introduced themselves. And agenda was reviewed.

**Attachment:** 2 Compound Semiconductor Materials Spring Meeting 2025 Agenda

**2 Review of Previous Meeting Minutes**

The TC Chapter reviewed the minutes of the previous meeting.

**Motion:** To approve the minutes of the previous meeting as written

**By / 2<sup>nd</sup>:** Yang Gan (HIT) / Ming Lu (*Perfect Crystal*)

**Discussion:** None

**Vote:** 16Y - 0 N, (Total 20 companies.) Motion Passed.

**Attachment:** 3 China CSM&HB-LED TC Joint Spring Meeting Minutes 20241205

**3 SEMI Staff Report**

Sara Ma (SEMI China) gave the SEMI Staff Report. Of note:

**Action Item:**

- SEMI International Standards Overview
- SEMI Standards Publications
- 2025 Critical Dates for SEMI Standards Ballots



- NARSC Members
- Organization chart

**Attachment:** 4 SEMI Staff Report

## 4 Liaison Reports

### 4.1 Compound Semiconductor Materials Europe TC Chapter

Sara Ma(SEMI) reported for the Compound Semiconductor Materials Europe TC Chapter. Of note:

**Action Item:**

- Meeting Information
- Leadership / Leadership Changes
- Committee Structure Changes
- Organization Chart
- Ballot Results
- Task Force Highlights

**Attachment:** 5 EU CSM Liaison Report November 2024

### 4.2 Compound Semiconductor Materials Japan TC Chapter

Sara Ma (SEMI) reported for the Compound Semiconductor Materials Japan TC Chapter. Of note:

**Action Item:**

- Meeting Information
- Leadership
- Organization Chart
- Ballot Results
- Task Force Highlights

**Attachment:** 6 CSM\_JA TC Chapter Liaison Report\_March 2025\_R1

## 5 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

**6769C- New Standard: Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic Effect**

**Failed** and returned to the TF for rework

1.1 Document 6769, New Standard: Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic Effect

**Motion:** Jiaqi Zhang (Perfect Crystal) moved that This Document failed TC Chapter review and work will be discontinued.



By / 2nd: Ming Lu(Perfect Crystal) / Guoqiao Tao(Enkris)

**Discussion:** None

**Vote:** 19 in favor and 0 opposed. (Total 20 companies. 1 companies abstain.) Motion passed.

Attachment: None

## 6 Subcommittee and Task Force Reports

### a) *Silicon Carbide Substrate Task Force*

Jiaqi Zhang (Perfect Crystal) reported for the Silicon Carbide Substrate Task Force. This report contained information on:

#### **Action Item:**

- Introduced the task force's leaders and members.
- Documents in Development:
  - Doc.6767: New Standard: Test Method for GBIR, SBIR, GF3R, SFQR and SORI of Silicon Carbide Wafers by Oblique Incident Interference Method
  - Doc.6769: New Standard: Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic
- Specific Work
  - Dec. 5, 2024, SEMI Standards Compound Semiconductor China TC Chapter Meeting Winter 2024.
  - Dec. 5, 2024--May. 21, 2025 Revise 6769C as required, submit it for a global vote, and await the voting results.
  - May. 21, 2025-- Discuss how to revise the opposing opinions on 6769C and hope to abolish the document.

**Attachment:** 7 SEMI China CS Std. Technical Committee Silicon Carbide substrate Task Force 20250617

## 7 Old Business

- a) *Refer to Table 12 Previous Meeting Action Items*

## 8 New Business

None

## 9 Next Meeting and Adjournment

The next meeting of the Compound Semiconductor Materials & HB-LED China TC Chapter is scheduled for TBD, 2025 in China.

For more information, please visit Standards Calendar at <http://www.semi.org/en/standards>



Adjournment: 15:35.

Respectfully submitted by:

Sara Ma

SEMI China

Phone: 021-6027-8578

Email: sarama@semi.org

Minutes tentatively approved by:

Jiangbo Wang (HC SEMITEK), Compound Semiconductor Materials Committee and HB-LED Committee China TC Chapter Co-chair	06/27/2025
Guoyou Liu (CRRC TIMES), Compound Semiconductor Materials Committee and HB-LED Committee China TC Chapter Co-chair	06/30/2025

**Table 13 Index of Available Attachments#1**

<i>Title</i>	<i>Title</i>
1 Chinese SEMI Standard Meeting Reminders	2 Compound Semiconductor Materials Spring Meeting 2025 Agenda
3 China CSM&HB-LED TC Joint Spring Meeting Minutes 20241205	4 SEMI Staff Report
5 EU CSM Liaison Report November 2024	6 CSM_JA TC Chapter Liaison Report_March 2025_R1
7 SEMI China CS Std. Technical Committee Silicon Carbide substrate Task Force 20250617	8 SEMI China CS Std. Technical Committee Silicon Carbide substrate Task Force - 废止说明

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at [www.semi.org](http://www.semi.org). For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.